Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

09/829,971

Examiner

KICHISE, MIKI Art Unit

CHUONG T. HO

2664

SEARCHED					
Class	Subclass	Date	Examiner		
370 370 370	352 / HOI × 392	08/01/05	CH		
709	224				
370	H32				
370	<i>53</i> 2		·		
370	533				
370	534				
370	535 ×				
370	536 \$				
370	537				
370	538				
370	539				
370	540				
370	541				
370	542				

INTERFERENCE SEARCHED					
Class	Subclass	Da	te ,	Exar	niner
370	401	08/0	1/05	0	Н
370	35 L				
370	535				
370	536				
370	545			١	<u> </u>

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
WEST (TEXT SEARCH	08/01/05	CH
CLASS SEARCH		
EAST	०९/०२/०३	CH
STN		
IEEE		
Consulting with	08/03/05	01-1
Willington Chin SPE AU 2664		
SPE AU 2664		
·		
	,	

Search Notes



Application/Control	No.
---------------------	-----

Applicant(s)/Patent under Reexamination

09/829,971

Examiner

KICHISE, MIKI Art Unit

CHUONG T. HO

2664

SEARCHED					
Class	Subclass	Date	Examiner		
370	543	08/01/05	01		
370	544				
370	5451				
370	366				
370	467√				
370	545,				
370	466.		\		
			,		

INT	ERFERENC	CE SEARCHI	ED
Class	Subclass	Date	Examiner
370	401	08/01/05	CH
			,
	•		

(INCLUDING SEARCH STRATEGY)			
-		DATE	EXMR
•			
································			
	,		
·			
<u></u> .			
		•	
•			